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FDG6335N 20V N-Channel PowerTrench[®] MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized use in small switching regulators, providing an extremely low $R_{DS(ON)}$ and gate charge (Q_G) in a small package.

Applications

- DC/DC converter
- Power management
- Loadswitch

Features

- $\mbox{ or } A, \mbox{ 20 V}. \qquad R_{DS(ON)} = 300 \mbox{ m} \Omega \ @ \ V_{GS} = 4.5 \ V \\ R_{DS(ON)} = 400 \mbox{ m} \Omega \ @ \ V_{GS} = 2.5 \ V \\ \label{eq:DS(ON)}$
- Low gate charge (1.1 nC typical)
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- Compact industry standard SC70-6 surface mount package



The pinouts are symmetrical; pin 1 and pin 4 are interchangeable.

Absolute Maximum Ratings T_{A=25°C} unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain-Sourc	ource Voltage		20	V	
V _{GSS}	Gate-Source	e Voltage		± 12	V	
I _D	Drain Curre	nt – Continuous	(Note 1)	0.7	A	
		– Pulsed		2.1		
PD	Power Dissi	pation for Single Operation	(Note 1)	0.3	W	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	
. 3, . 310	- - J - J - J		9			
	I Charact	5	5			
Therma	I Charact	5		415	°C/W	
Therma _{R₀JA} Packag	I Charact	teristics sistance, Junction-to-Ambie g and Ordering Ir	ent (Note 1)	-	°C/W	
Therma R _{eJA}	I Charact	sistance, Junction-to-Ambie	ent (Note 1)	415 Tape width	°C/W	

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 Typ
 Max
 Units

 Μα
 V

 14
 mV/°C

 14
 μA

 100
 nA

 -100
 nA

Min

20

5

10

ns

On Cha	racteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 250 \ \mu A$	0.6	1.1	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		-2.8		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{c} V_{GS} = 4.5 \; V, I_D = 0.7 \; A \\ V_{GS} = 2.5 \; V, I_D = 0.6 \; A \\ V_{GS} = 4.5 \; V, I_D = 0.7 \; A, \; T_J {=} 125^\circ C \end{array} $		180 293 247	300 400 442	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	1			A
g fs	Forward Transconductance	$V_{DS} = 5 V$, $I_{D} = 0.7 A$		2.8		S
Dynami	c Characteristics	-				
Ciss	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		113		pF
Coss	Output Capacitance	f = 1.0 MHz		34		pF
Crss	Reverse Transfer Capacitance	7		16		pF

T_A = 25°C unless otherwise noted

 $V_{GS} = 0 V$,

Test Conditions

 $I_{D} = 250 \ \mu A$

 $I_D = 250 \,\mu$ A, Referenced to 25° C

 $V_{\text{DS}} = 16 \text{ V}, \quad V_{\text{GS}} = 0 \text{ V}$

 $V_{GS} = 12 \text{ V}, \quad V_{DS} = 0 \text{ V}$

 $V_{GS} = -12 \ V, \quad V_{DS} = 0 \ V$

Electrical Characteristics

Parameter

Breakdown Voltage Temperature

Zero Gate Voltage Drain Current

Gate-Body Leakage, Forward

Gate-Body Leakage, Reverse

Drain-Source Breakdown

Symbol

 $\mathsf{BV}_{\mathsf{DSS}}$

 ΔBV_{DSS}

 ΔT_{J}

 I_{DSS}

I_{GSSF}

 I_{GSSR}

Off Characteristics

Voltage

Coefficient

Turn–On Rise Time	$V_{GS} = 4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		7	15	ns
Turn-Off Delay Time			9	18	ns
Turn–Off Fall Time			1.5	3	ns
Total Gate Charge	$V_{DS} = 10 V, I_D = 0.7 A,$		1.1	1.4	nC
Gate-Source Charge	$V_{GS} = 4.5 V$		0.24		nC
Gate-Drain Charge			0.3		nC
	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$\begin{tabular}{ c c c c c }\hline Turn-Off Delay Time & & & & & & & & \\ \hline Turn-Off Fall Time & & & & & & & & & \\ \hline Total Gate Charge & & V_{DS} = 10 \ V, & I_D = 0.7 \ A, & & & & & & & & \\ \hline Gate-Source Charge & & & & & & & & & & & & \\ \hline \end{tabular}$	Turn-Off Delay Time	Turn-Off Delay Time 9 Turn-Off Fall Time 1.5 Total Gate Charge V _{DS} = 10 V, I _D = 0.7 A, V _{GS} = 4.5 V Gate-Source Charge 0.24	$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$

Drain-Source Diode Characteristics and Maximum Ratings

ls	Maximum Continuous Drain–Source Diode Forward Current				0.25	А
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V,$	$I_{S} = 0.25 \text{ A}$ (Note 2)	0.74	1.2	V

Notes:

1. R_{0,LA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0,LC} is guaranteed by design while R_{0,LA} is determined by the user's board design. R_{0,LA} = 415°C/W when mounted on a minimum pad.

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

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